

半導体バリア CuInSe_2 , CuGaSe_2 を用いた 磁気トンネル接合におけるスピン依存伝導特性の理論解析

Theoretical study for magnetic tunneling junctions

including semiconductor barriers CuInSe_2 and CuGaSe_2

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High magnetoresistance (MR) ratios and low resistance-area products (RA) are required for magnetic tunneling junctions (MTJs) to realize ultrahigh-density hard disk drives and Gbit-class magnetoresistive random access memories (MRAMs). Recently, Kasai *et al.* observed relatively high MR ratios keeping low RA in MTJs with new semiconductor barriers $\text{CuIn}_{1-x}\text{Ga}_x\text{Se}_2$ (CIGS) [1]. Inspired by this founding, we investigated transport properties of magnetic tunneling junctions (MTJs) with semiconductor barriers CuInSe_2 (CIS) and CuGaSe_2 (CGS) by means of the first-principles-based calculations and the Landauer formula. We also took into account the Coulomb repulsion U for the Cu $3d$ states in the barriers to investigate the band-gap dependence of the MR ratio systematically. Figure 1(a) shows a \mathbf{k}_{\parallel} dependence of the majority-spin transmittance in the Fe/CIS/Fe MTJ with parallel magnetization of Fe electrodes. We can see a sharp peak around $\mathbf{k}_{\parallel}=(0,0)$, which is a clear evidence of the coherent tunneling of the wave functions. We found from complex band structure of CIS that the Δ_1 states provide dominant contributions to this peak [2]. We confirmed that the spin-dependent coherent tunneling of the Δ_1 wave functions also occurs in the CGS-based MTJs. Figure 1(b) shows the MR ratios and RA values of the CIS-, CGS-, and MgO-based MTJs. We see that the MR ratios in the CGS-based MTJs are around 300%, which is much higher than those of the CIS-based MTJs around 70%. We also found that the RA values of the CIS- and CGS-based MTJs are much smaller than those of the MgO-based MTJs even if the MgO barrier is quite thin (~ 1.24 nm), which is consistent with experimental results in the CIGS-based MTJs [1].

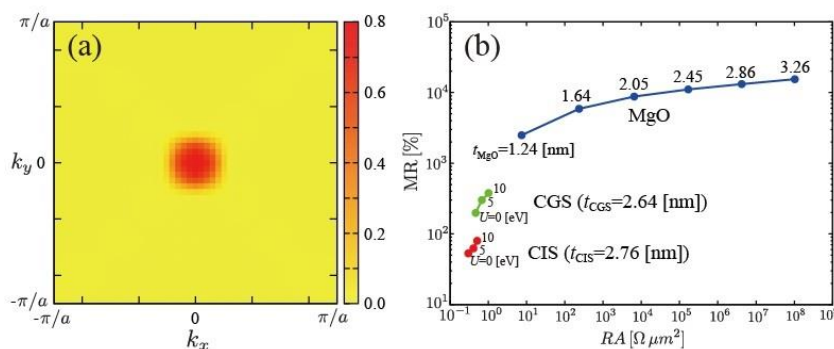


Fig. 1. (a) The \mathbf{k}_{\parallel} dependence of the majority-spin transmittance for $U=5$ eV in the CIS-based MTJ with parallel magnetization of Fe electrodes. (b) The MR ratios and RA values of the CIS-, CGS-, and MgO-based MTJs. The barrier thickness (t_{CIS} , t_{CGS} , or t_{MgO}) is defined as the distance between two Fe layers closest to the barrier.

[1] S. Kasai *et al.*, Appl. Phys. Lett. **109**, 032409 (2016).

[2] K. Masuda and Y. Miura, arXiv:1609.07713 (to appear in Jpn. J. Appl. Phys.).